



INTERNATIONAL STANDARD



**Semiconductor devices –
Part 18-1: Semiconductor bio sensors – Test method and data analysis for
calibration of lens-free CMOS photonic array sensors**

INTERNATIONAL
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COMMISSION

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CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope.....	8
2 Normative references	8
3 Terms and definitions	8
4 Measurement setup	9
4.1 General.....	9
4.2 Measurement system.....	9
4.2.1 Overall system.....	9
4.2.2 Dark box.....	11
4.2.3 Light source.....	11
4.2.4 Sensor board.....	11
4.2.5 Configuration parameters	12
5 Measurement.....	12
5.1 General.....	12
5.2 Case 1: Fixed wavelength (λ) of light	12
5.2.1 Planarization: At fixed λ and incident light intensity.....	12
5.2.2 Linearity: Varying the incident light intensity with a fixed wavelength	14
5.3 Case 2: Various wavelength (λ) of light	14
6 Data analysis.....	14
6.1 Data plot.....	14
6.1.1 General	14
6.1.2 Sensor screening.....	16
6.2 Planarization characteristics	16
6.2.1 Criterion of determining the reference pixel	16
6.2.2 Lookup table of representative value for planarization calibration of each pixel.....	17
6.3 Linearity.....	17
6.3.1 Criterion of linear region of each pixel	17
6.3.2 Criterion of light intensity effective area for linearity.....	18
6.3.3 Lookup table of the representative value for linearity calibration of each pixel	18
7 Calibration.....	19
7.1 Calibration lookup table	19
7.2 Reference for establishing the representative output value in the effective area.....	20
8 Test report.....	21
Annex A (informative) Test report	23
A.1 Test environment specification.....	23
A.2 Specification of CMOS photonic array sensor	24
A.3 Calibration lookup table	24
A.4 Representative value look up table for planarization calibration of the sensor	24
A.5 Representative value look up table for linearity calibration of the sensor.....	25
Bibliography.....	26
Figure 1 – Example of box plot.....	9

Figure 2 – Example of measurement system with integrating sphere.....	10
Figure 3 – Example of measurement system with incident parallel light.....	10
Figure 4 – Example of photoelectric measurement schematic	11
Figure 5 – Measurement flow	12
Figure 6 – n trial data of frame capture	13
Figure 7 – Two frame subtracted data	13
Figure 8 – Dark frame subtracted data	14
Figure 9 – Example of output electric signal non-linearity of 2D pixel array	15
Figure 10 – Example of output electric signal non-linearity of one row of pixels	15
Figure 11 – Example of one pixel’s output electric signal according to input light power.....	16
Figure 12 – Example of determining the reference pixel.....	17
Figure 13 – Example of the representative value for planarization.....	17
Figure 14 – Example of light intensity effective area for linearity	18
Figure 15 – Example of the representative value for linearity	19
Figure 16 – Example of a simplified pixel structure and cross-sectional view with bio reaction	19
Figure 17 – Example of the representative value of the sensor	21
Table 1 – Calibration lookup table	20
Table 2 – Representative value table of the sensor	21

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SEMICONDUCTOR DEVICES –

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for calibration of lens-free CMOS photonic array sensors**

FOREWORD

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International Standard IEC 60747-18-1 has been prepared by subcommittee 47E: Discrete semiconductor devices, of IEC technical committee 47: Semiconductor devices.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
47E/643A/FDIS	47E/657/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of the IEC 60747 series, published under the general title *Semiconductor devices*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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INTRODUCTION

The IEC 60747-18 series on semiconductor bio sensors is expected to be composed of the following parts:

- IEC 60747-18-1 defines the test method and data analysis for calibration of lens-free CMOS photonic array sensor
- IEC 60747-18-2¹ defines the evaluation process of lens-free CMOS photonic array sensor package module
- IEC 60747-18-3² defines the fluid flow characteristics of lens-free CMOS photonic array sensor package module with fluidic system

The IEC 60747-18 series includes subjects such as noise analysis, long-term reliability tests, test methods for lens-free CMOS photonic array sensor package module under patchable environments, test methods under implantable environments, etc.

The International Electrotechnical Commission (IEC) draws attention to the fact that it is claimed that compliance with this document may involve the use of patents given in several subclauses as indicated in the table below. These patents are held by their respective inventors under license to SOL Inc.:

KR1020150081134	[SOL]	The method of calibration of photon sensor pixel array by evaluating its characteristic	Subclauses 5.1, 5.2.1, 5.2.2, 5.3, 7.1
PCT/KR2016/006109	[SOL]	METHOD FOR CORRECTING OPTICAL SENSOR ARRAY MODULE THROUGH CHARACTERISTIC EVALUATION	Subclauses 5.1, 5.2.1, 5.2.2, 5.3, 7.1 Clause 6
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¹ Under preparation. Stage at the time of publication: IEC/PRVC 60747-18-2:2019.

² Under preparation. Stage at the time of publication: IEC/PRVC 60747-18-3:2019.

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SEMICONDUCTOR DEVICES –

Part 18-1: Semiconductor bio sensors – Test method and data analysis for calibration of lens-free CMOS photonic array sensors

1 Scope

This part of IEC 60747 specifies the test methods and data analysis for the calibration of lens-free CMOS photonic array sensors. This document includes the test conditions of each process, configuration of lens-free CMOS photonic array sensors, statistical analysis of test data, calibration for planarization and linearity, and test reports.

2 Normative references

There are no normative references in this document.